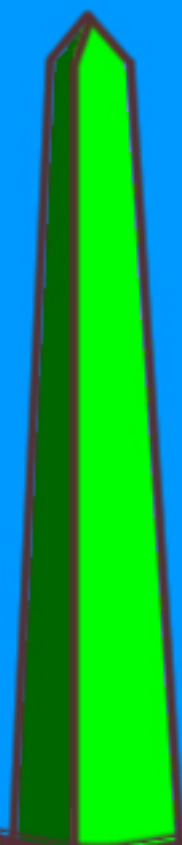


7th IEEE Latin-American Test Workshop  
**LATW2006**

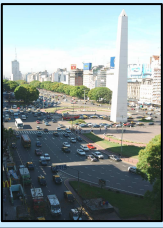


March 26-29, 2006  
Buenos Aires, Argentina

[www.latw.net](http://www.latw.net)

tttc





# 7th IEEE Latin American Test Workshop

Buenos Aires, Argentina  
March 26 - 29, 2006

## Call for Papers

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vargas@computer.org  
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R. Velazco Y. Zorian

The **IEEE Latin-American Test Workshop (LATW)** provides an annual forum for test and fault tolerance professionals and technologists from Latin America and all over the world to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. The best papers of the **7<sup>th</sup> LATW** will be invited to be re-submitted to the *IEEE Design and Test of Computers*.

### Topics of interest include, but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Dependability Estimation
- Design and Synthesis for Testability
- Design Verification/Validation
- E-Beam and Thermal Testing
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI - Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization

### Topic Coordinators:

L. Anghel, *TIMA-INPG - France*  
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A. Veneris, *Univ. of Toronto - Canada*  
S. R. Vergilio, *UFPR - Brazil*

### Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper. **PDF electronic submissions should be done via the workshop webpage:**

[www.latw.net](http://www.latw.net)

Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop webpage. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information, please contact one of the Program Co-Chairs:

### Eduardo Bezerra

Catholic University - PUCRS  
Brazil  
eduardob@inf.pucrs.br

### Victor Champac

Instituto Nacional de Astrofísica,  
Óptica y Electrónica (INAOE), Mexico  
champac@inaoep.mx

**Submission Deadline:** November 11th, 2005.

**Notification of Acceptance:** December 16th, 2005.

**Camera Ready:** January 18th, 2006.

**LATW'05** will be held in **Buenos Aires**, Argentina. The south America's most sophisticated and elegant capital city, **Buenos Aires** is the home to 13 million proud port city dwellers, or *porteños*. The city's air of sophistication and pride is more European than South American in flavor. **Buenos Aires'** heart boasts bustling streets, grand avenues, old-time cafes and stylish restaurants. The *porteños* (locals) are renowned for their flair and cockiness, while the city remains a safe, vibrant, and a cosmopolitan capital.

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